



Title : Qualification Report for PCN : P5C6AAB

Date : Jan. 07, 2016

Affected devices :

Customer Name : SEMI DICE INCORPORATED

Customer Code : 0004014801

Product	Customer Part Number	BBB	Drawing
PCFC20N60W		Y	N

Qualification Test Summary :

Qualification Plan	Device	Package	Process	No. of Lots
Q20120263	FCP20N60	TO220	Super-FET1	3

Test Description:	Condition:	Standard:	Duration:	Results:
High Temperature Reverse Bias	480V,150C	JESD22-A108	1000 hrs	0/231
High Temperature Gate Bias	150C, 30V	JESD22-A108	1000hrs	0/231
Highly Accelerated Stress Test	85%RH, 130C,42V	JESD22-A110	96hrs	0/231
Temperature Cycle	-65C, 150C	JESD22-A104	500 cyc	0/231
Power Cycle	On/Off=3.5min, Delta Tj=100C	MIL-STD-750 M1036	8572 cyc	0/231
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/231

Qualification Plan	Device	Package	Process	No. of Lots
Q20120268	FCA47N60	TO3P	Super-FET1	1

Test Description:	Condition:	Standard:	Duration:	Results:
High Temperature Reverse Bias	480V,150C	JESD22-A108	1000 hrs	0/77
High Temperature Gate Bias	150C, 30V	JESD22-A108	1000hrs	0/77
Highly Accelerated Stress Test	85%RH, 130C,42V	JESD22-A110	96hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cyc	0/77
Power Cycle	5min on/3.5min off, Delta Tj=100C	MIL-STD-750 M1036	6000 cyc	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77

The selection methodology of qualification vehicles is aligned with JESD47 and if automotive devices are impacted by the PCN the selection of qualification vehicles is also align with the requirements in AEC-Q100 or AEC-Q101

Please contact your local Customer Quality Engineer if you have any questions concerning this data.